

Title (en)

Method and apparatus for detecting oscillator stuck faults in a level sensitive scan design (LSSD) system.

Title (de)

Verfahren und Gerät zur oszillatorhaftenden Fehlererkennung in einem pegelempfindlichen Abfragedesignsystem.

Title (fr)

Procédé et dispositif de détection d'erreur permanente d'oscillateur dans un système de design selon le principe du balayage sensible aux niveaux.

Publication

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Application

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Priority

US 43506889 A 19891113

Abstract (en)

A method and apparatus for identifying stuck faults in an oscillator used for providing a oscillator input signal (12) to an integrated circuit chip of the type conforming to a Level Sensitive Scan Design (LSSD) system and testing technique. A pair of shift register latches (SRLs) (20,30) are provided in the integrated circuit chip having a logical one signal applied to a data input of the SRLs. The oscillator input signal is applied to a data clock input of a first one (20) of the SRLs and an inverted oscillator input signal is applied to the data clock input of a second one (30) of the SRLs. Then the scan data output (SDO) of the test SRLs is detected responsive to the applied oscillator and inverted oscillator input signals to identify a stuck fault.

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